FAIRCHILD SEMICONDUCTOR®

February 2007

FDMS8690
N-Channel Power Trench® MOSFET
30V, 27A, 9.0mΩ

Features

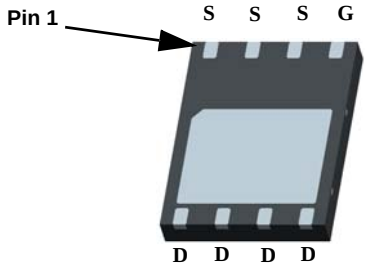
- Max $r_{DS(on)}$ = 9.0mΩ at V_{GS} = 10V, I_D = 14.0A
- Max $r_{DS(on)}$ = 12.5mΩ at V_{GS} = 4.5V, I_D = 11.5A
- High performance trench technology for extremely low $r_{DS(on)}$ and gate charge
- Minimal Qgd (2.9nC typical)
- RoHS Compliant

General Description

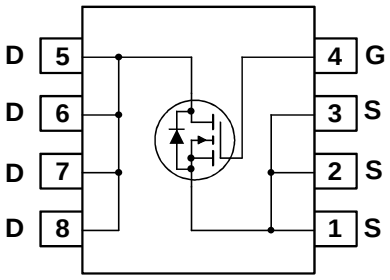
This device has been designed specifically to improve the efficiency of DC/DC converters. Using new techniques in MOSFET construction, the various components of gate charge and capacitance have been optimized to reduce switching losses. Low gate resistance and very low Miller charge enable excellent performance with both adaptive and fixed dead time gate drive circuits. Very low $r_{DS(on)}$ has been maintained to provide an extremely versatile device.

Application

- High Efficiency DC-DC converters.
- Notebook CPU power supply
- Multi purpose Point of Load



Power 56 (Bottom view)



MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V_{DS}	Drain to Source Voltage			30	V
V_{GS}	Gate to Source Voltage			±20	V
I_D	Drain Current -Continuous (Package limited)	T_C = 25°C		27	A
	-Continuous (Silicon limited)	T_C = 25°C		52	
	-Continuous	T_A = 25°C	(Note 1a)	14	
	-Pulsed			100	
P_D	Power Dissipation	T_C = 25°C		37.8	W
	Power Dissipation	T_A = 25°C	(Note 1a)	2.5	
T_J, T_{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	3.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	

Package Marking and Ordering Information

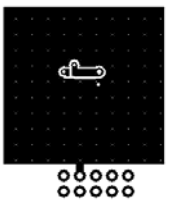
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS8690	FDMS8690	Power 56	13”	12mm	3000 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250μA, V_{GS} = 0V	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250μA, referenced to 25°C		34		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 24V , V_{GS} = 0V			1	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±20V, V_{DS} = 0V			±100	nA
On Characteristics						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 250μA	1	1.6	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250μA, referenced to 25°C		-4.5		mV/°C
$r_{DS(on)}$	Drain to Source On Resistance	V_{GS} = 10V, I_D = 14.0A		7.4	9.0	mΩ
		V_{GS} = 4.5V, I_D = 11.5A		9.9	12.5	
		V_{GS} = 10V, I_D = 14.0A, T_J = 125°C		10.6	13.3	
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 15V, V_{GS} = 0V, f = 1MHz		1260	1680	pF
C_{oss}	Output Capacitance			535	715	pF
C_{rss}	Reverse Transfer Capacitance			80	120	pF
R_g	Gate Resistance	f = 1MHz		1.1	5.0	Ω
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 15V, I_D = 1.0A, V_{GS} = 10V, R_{GEN} = 6Ω		8	16	ns
t_r	Rise Time			1.8	10	ns
$t_{d(off)}$	Turn-Off Delay Time			26	42	ns
t_f	Fall Time			19	35	ns
$Q_{g(TOT)}$	Total Gate Charge at 10V	V_{GS} = 0V to 10V; V_{DD} = 15V, I_D = 14.0A		18.8	27	nC
$Q_{g(5)}$	Total Gate Charge at 5V	V_{GS} = 0V to 5V; V_{DD} = 15V, I_D = 14.0A		10	14	nC
Q_{gs}	Gate to Source Gate Charge	V_{DD} = 15V, I_D = 14.0A		3.5		nC
Q_{gd}	Gate to Drain “Miller” Charge	V_{DD} = 15V, I_D = 14.0A		2.9		nC
Drain-Source Diode Characteristics						
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0V, I_S = 2.1A (Note 2)		0.7	1.2	V
t_{rr}	Reverse Recovery Time	I_F = 14.0 A, di/dt = 100A/μs			45	ns
Q_{rr}	Reverse Recovery Charge				33	nC

Notes:

1: $R_{\theta JA}$ is determined with the device mounted on a 1in^2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a. 50°C/W when mounted on a 1 in^2 pad of 2 oz copper

b. 125°C/W when mounted on a minimum pad of 2 oz copper

2: Pulse Test: Pulse Width < 300μs, Duty cycle < 2.0%.

Typical Characteristics T_J = 25°C unless otherwise noted

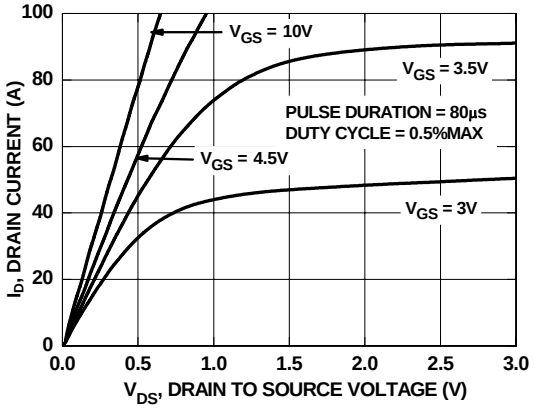


Figure 1. On-Region Characteristics

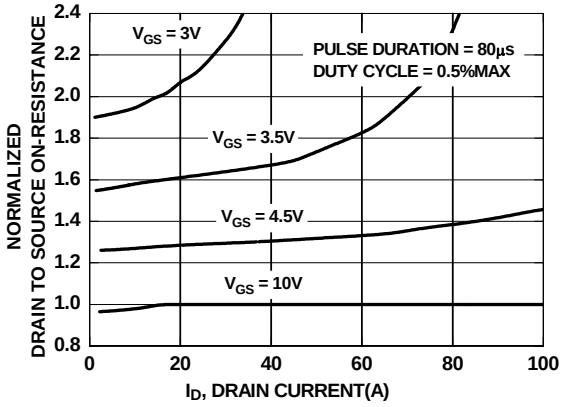


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

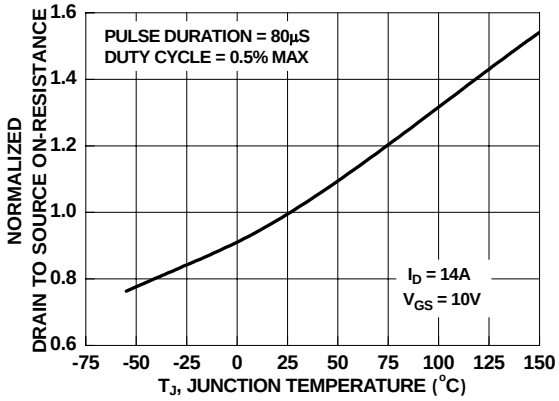


Figure 3. Normalized On-Resistance vs Junction Temperature

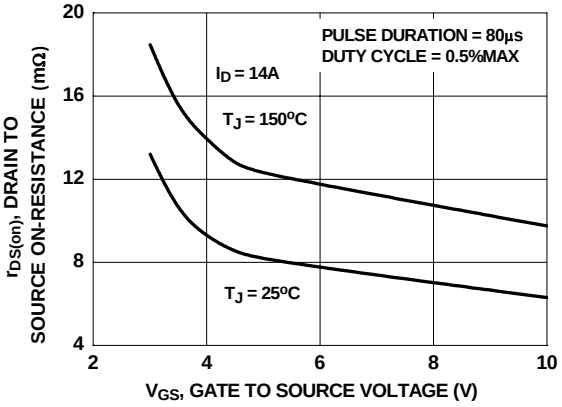


Figure 4. On-Resistance vs Gate to Source Voltage

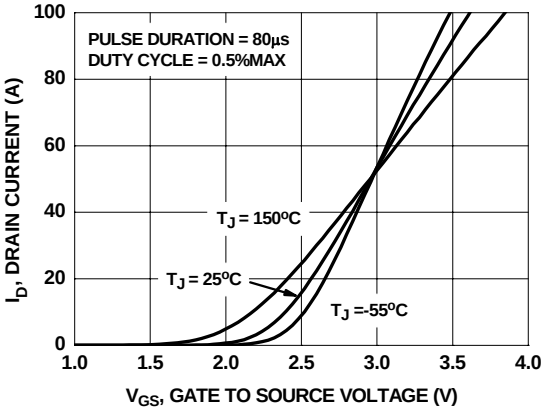


Figure 5. Transfer Characteristics

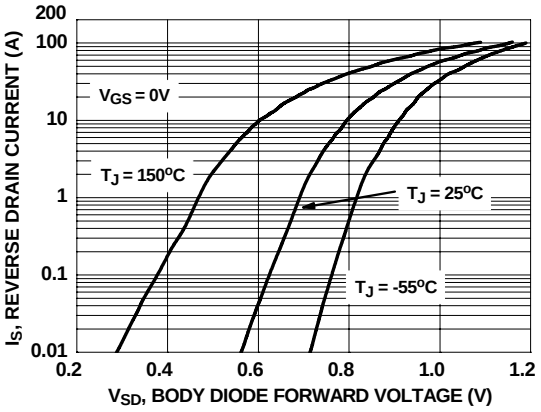


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

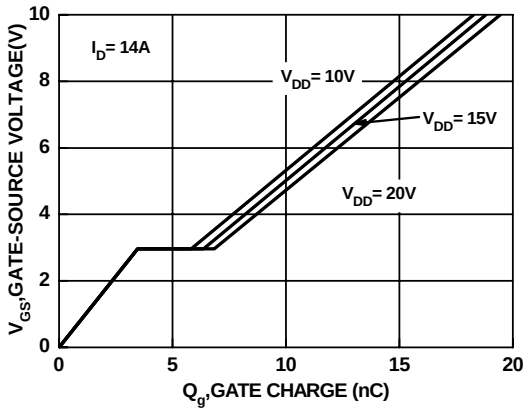


Figure 7. Gate Charge Characteristics

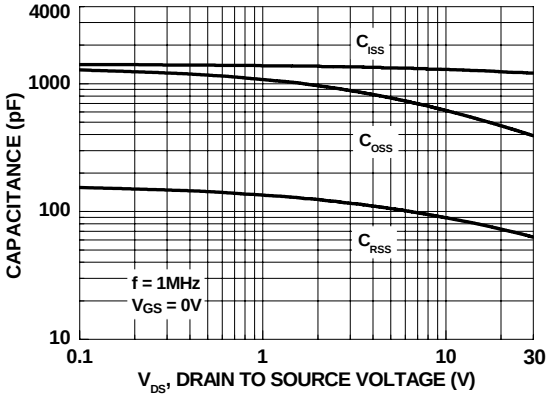


Figure 8. Capacitance vs Drain to Source Voltage

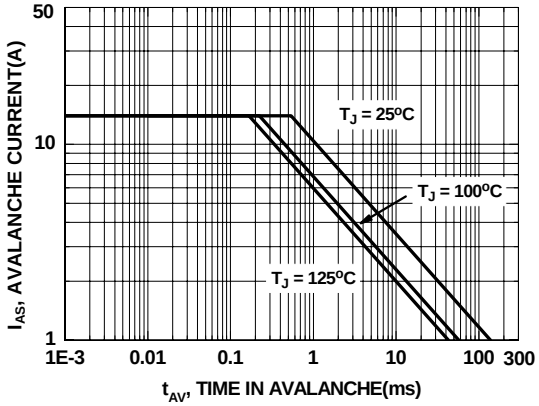


Figure 9. Unclamped Inductive Switching Capability

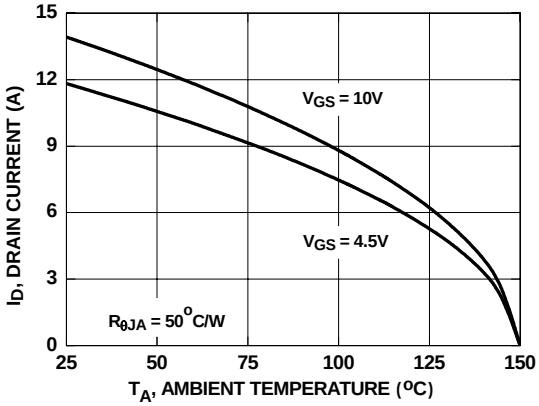


Figure 10. Maximum Continuous Drain Current vs Ambient Temperature

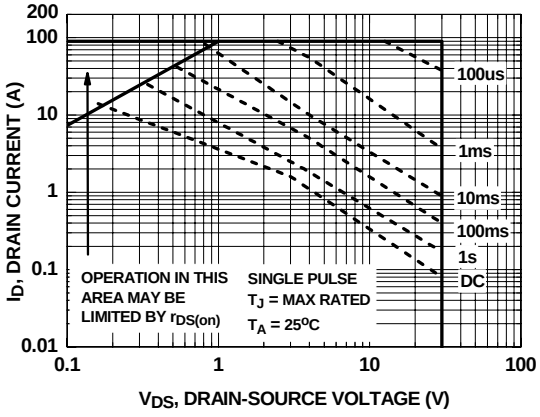


Figure 11. Forward Bias Safe Operating Area

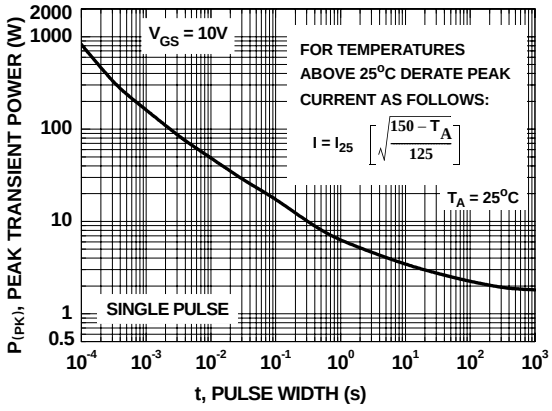


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25°C unless otherwise noted

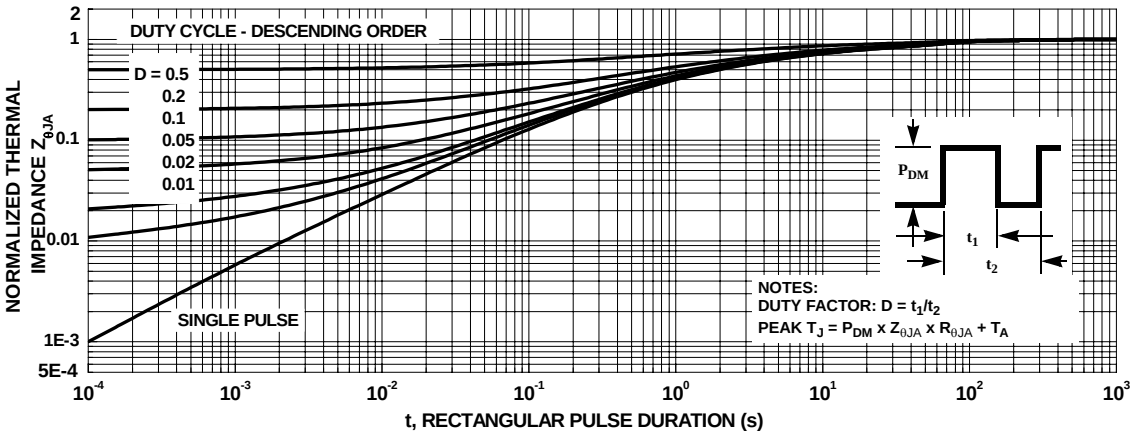
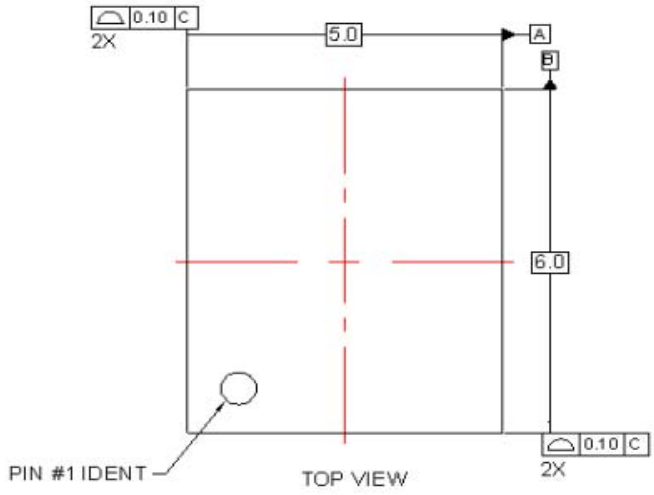
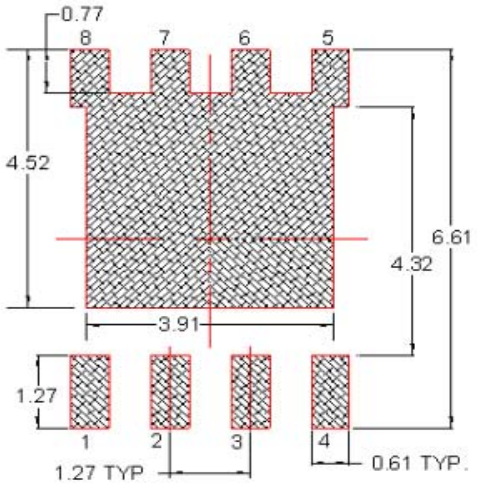
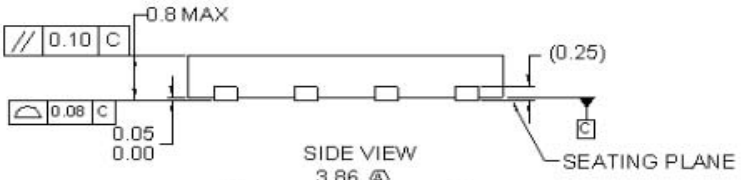


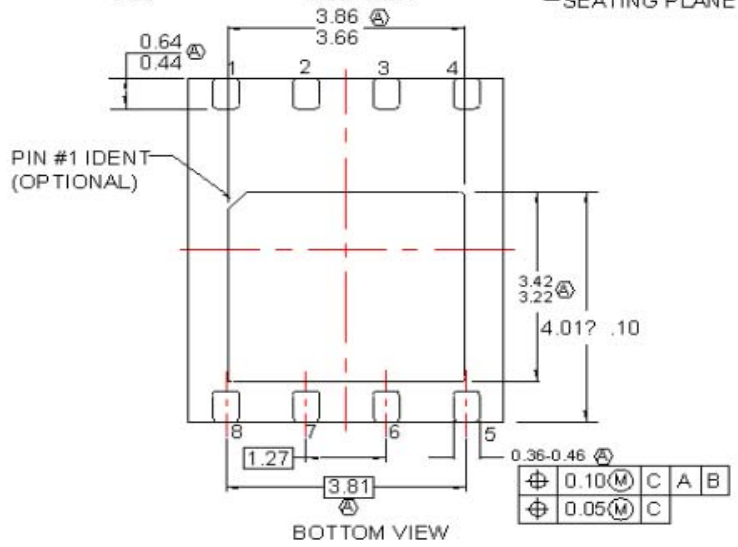
Figure 13. Transient Thermal Response Curve





RECOMMENDED LAND PATTERN





NOTES:

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C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

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